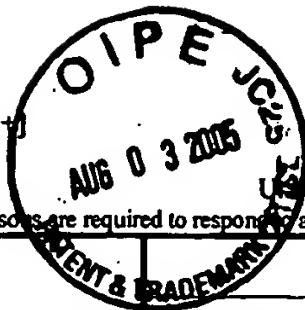


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PATENT & TRADEMARK

Application Number  
Filing Date  
First Named Inventor  
Group Art Unit  
Examiner Name

09/836,449

April 17, 2001

Stephen J. FONASH

2812

Richard A. Booth

Sheet

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of

1

Attorney Docket Number

201009-007000

### U.S. PATENT DOCUMENTS

Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
JKY		5,594,171		Ishida et al.	January 14, 1997	

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		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>3</sup> (if known)				
JKY			EP 0 895 276 A1		Bruno Murani	March 2, 1999		

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JKY		Supplementary Partial European Search Report	
		FURUKAWA, et al. Nickel Surface Micromachining, Sixth International Symposium on Micro Machine and Human Science, 1995, pp. 161-165, IEEE.	
JKY		WALTER LANG, Silicon Microstructuring Technology, Materials Science and Engineering, Reports: A Review Journal R17 (1996), pp. 1-55.	

Examiner Signature	<i>Richard A. Booth</i>	Date Considered	02/23/06
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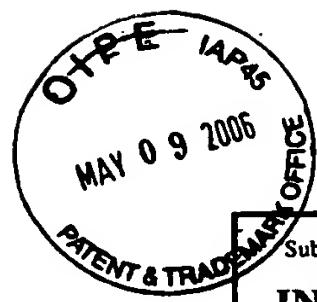
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				Application Number	09/836,449
				Filing Date	April 17, 2001
				First Named Inventor	Stephen J. FONASH
				An Unit	2812
				Examiner Name	Richard A. BOOTH
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/103		US-6,486,041	11/26/02	Henley, et al.	
/103		US-6,399,177	06/04/02	Fonash, et al.	
/103		US-6,372,608	04/16/02	Shimoda, et al.	
/103		US-6,225,192	05/01/01	Aspar, et al.	
/103		US-6,214,701	04/10/2000	Matsushita, et al.	
/103		US-6,158,824	12/12/00	Yonemura, et al.	
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/103		US-5,811,348	09/22/98	Matsushita, et al.	
/103		US-5,854,123	12/29/98	Sato, et al.	
/103		US-5,866,204	02/02/99	Robbie, et al.	
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/103		US-6,555,443	04/29/03	Artemann, et al.	
/103		US-6,774,010	08/10/04	Chu, et al.	
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/103		US-2002/0020053	2/21/2002	Fonash, et al.	

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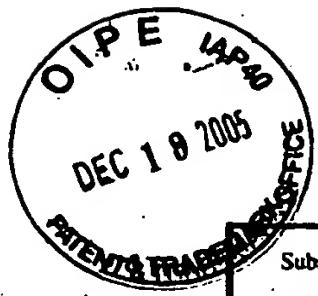
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Sheet

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*Complete if Known*

Application Number	09/836,449
Filing Date	April 17, 2001
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Art Unit	2812
Examiner Name	Richard A. BOOTH

Attorney Docket Number  
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Examiner Signature

*John J. Booth*

Date Considered

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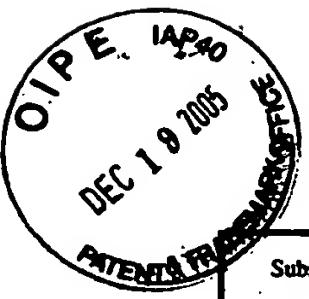
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/JG		CHENG, et al., Role of Electric Field on Formation of Silicon Nanowires, Journal of Applied Physics, Vol. 94, Number 2, July 15, 2003, 1190-1194 American Institute of Physics.	

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